Applicant(s)/Patent Under Application/Control No. Reexamination 10/535,029 WATANABE ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 Marc S. Zimmer 1712 **U.S. PATENT DOCUMENTS Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY US-2003/0232279 12-2003 Choi, Sang-Jun 430/280.1 Α US-5,604,039 В 02-1997 Chen et al. 428/447 С US-5,169,920 12-1992 Okawa, Tadashi 528/34 US-D US-E US-F US-G US-Н US-US-J Κ US-US-US-М **FOREIGN PATENT DOCUMENTS Document Number** Date Name Country Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R s Т **NON-PATENT DOCUMENTS**

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